# Electronic and structural properties of grain boundaries in electron-irradiated edge-defined film-fed growth silicon

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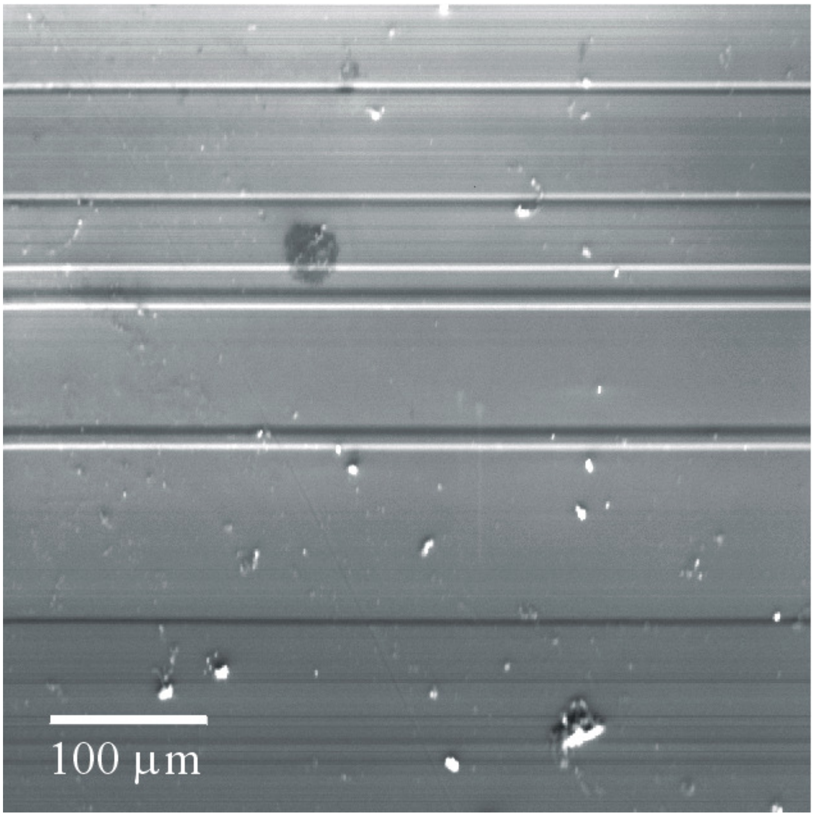

Fig.1

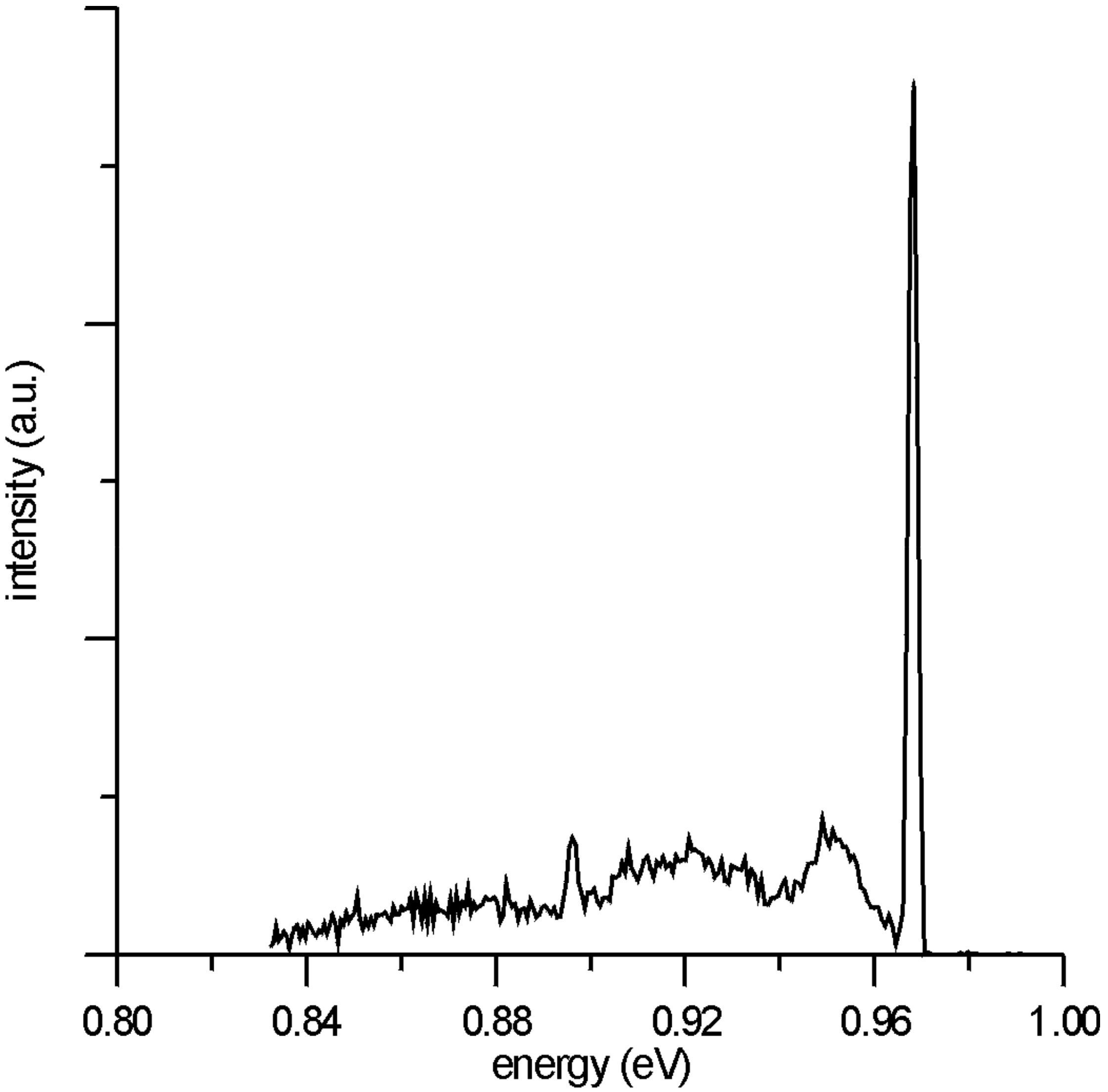

Fig 2

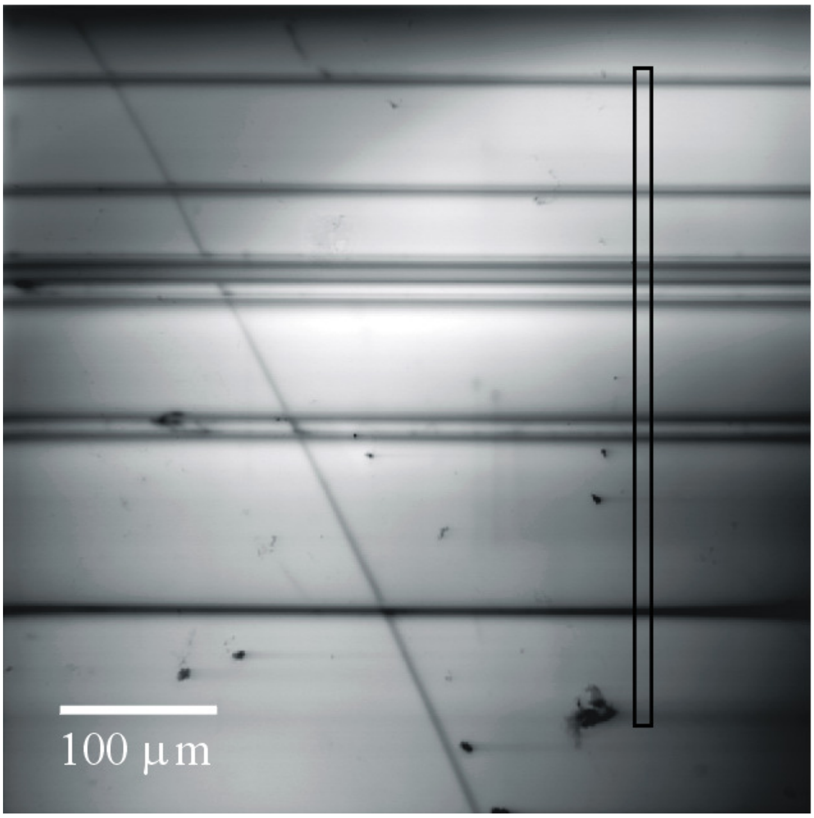

Fig 3(a)

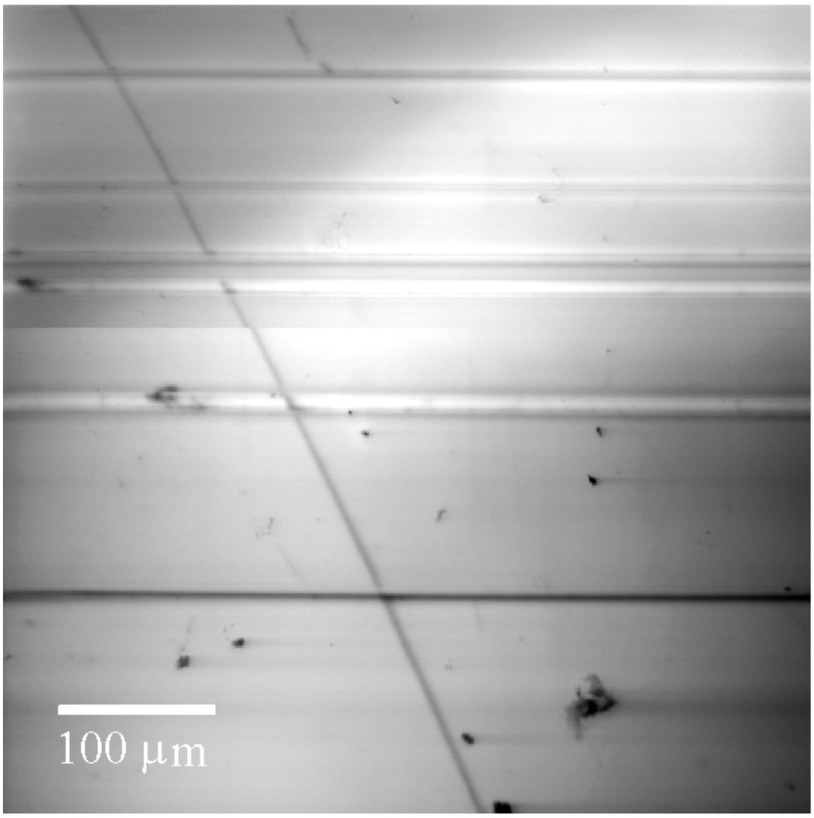

Fig 3(b)

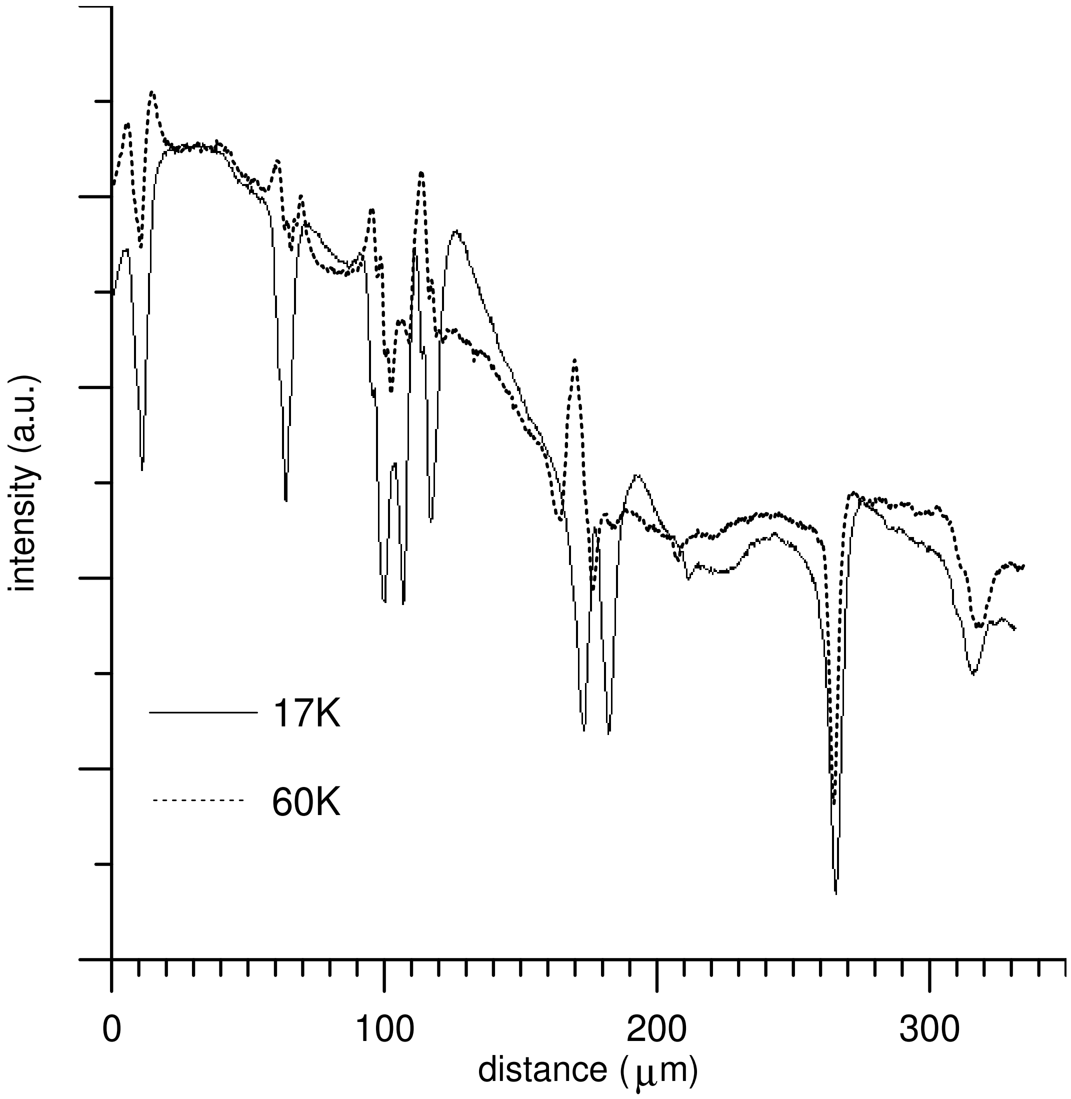

Fig 4

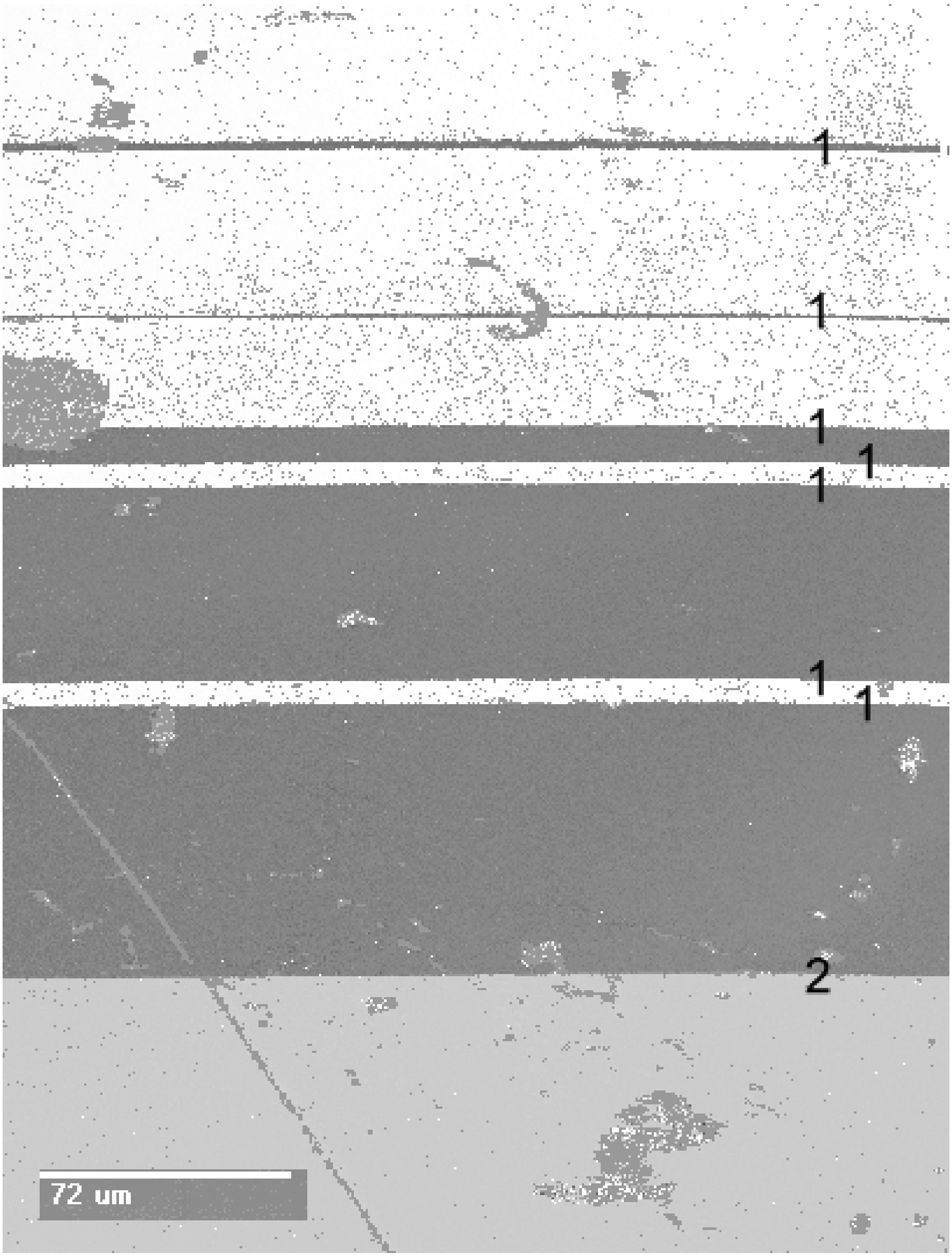

Fig 5